

Search Notes**Application/Control No.**

09/506,081

Examiner

John P. Lacyk

Applicant(s)/Patent under Reexamination

CHIU ET AL.

Art Unit

3735

SEARCHED

Class	Subclass	Date	Examiner
600	1-8		
606	194		
604	507-510,		
	96.01,		
	97.01		
	101.01-		
	103.14	2/3/2006	JPL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner